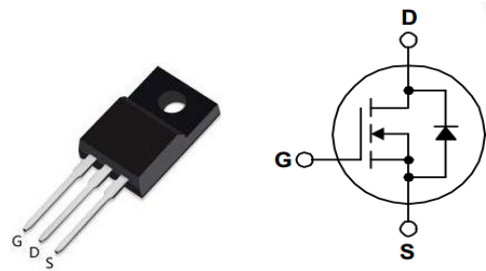


TH3N90PF

900V 3A 4.4Ω Silicon N-Channel Planar Power MOSFET

Features of this MOSFET are 150°C operating junction temperature and high repetitive peak current capability. These features combine to make this MOSFET a highly efficient, robust and reliable device for PDP driving applications.



Package view and circuit symbol

General Features

- $V_{DS}=900V, I_D=3A$
- Low ON Resistance, $R_{DS(on), typ.}=4.4\Omega @ V_{GS}=10V, I_D=1.5A$
- Low reverse transfer capacitance
- Low Qg for fast response
- Short fall & rise times for fast switching
- 100% single pulse avalanche energy Test

Applications

- Power switching application
- Digital amplifier
- Adapter and charger

Key Performance Parameters

Parameter	Value	Unit
$V_{DSS}, \min @ T_J = 25^\circ C$	900	V
$T_J, \text{maximum junction temperature}$	150	°C
$I_D @ T_C = 25^\circ C (\text{Silicon Limit})$	3	A
$I_{D,pulse} @ T_C = 25^\circ C, t_p \text{ limited by } T_{Jmax.}$	12	A
$R_{DS(on), typ.} @ T_J = 25^\circ C, V_{GS} = 10 V$	4.4	Ω
$E_{AS}, typ. @ T_J = 25^\circ C$	200	mJ



Marking Information

Product Name	Package	Marking
TH3N90PF	TO-220F	TH3N90PF

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Maximum Ratings (T_J = 25°C unless otherwise noted)

Parameter		Symbol	Value	Unit
Drain to Source Voltage		V _{DSS}	900	V
Gate to Source Voltage		V _{GSS}	±30	V
Drain Current _(Silicon limit)	T _C =25°C	I _D	3	A
Pulsed Drain Current	T _C =25°C tp limited by T _{vjmax}	I _{DM}	12	A
Avalanche energy, single pulse	L=10mH, R _g =25Ω	E _{AS}	200	mJ
Power Dissipation	T _C =25°C	P _D	46	W
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 To +150	°C
Lead Temperature for Soldering Purposes		T _L	270	

Thermal Characteristics

Parameter	Symbol	Max Value	Unit
Thermal Resistance, Junction-to-Case	R _{thJC}	2.7	°C/W
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	

Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Condition	Value			Unit
			min.	typ.	max.	
Drain-to-Source Breakdown Voltage	$B_{V_{DS}}$	$V_{GS}=0V, I_D=250\mu A$	900	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0V$ $V_{DS}=V_{DSS}$ $T_J=25^\circ\text{C}$	-	-	1	μA
		$V_{GS}=0V$ $V_{DS}=80\%V_{DSS}$ $T_J=125^\circ\text{C}$	-	-	10	
Gate-to-Source leakage Current	I_{GSS}	$V_{GS}=\pm 30V, V_{DS}=0V$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}$, $I_D=250\mu A$ $T_J=25^\circ\text{C}$	2.5	-	4.5	V
Drain-Source on-state resistance	$R_{DS(on)}$	$V_{GS}=10V$, $I_D=1.5A$ $T_J=25^\circ\text{C}$	-	4.4	5.3	Ω
Gate resistance	R_g	$V_{GS}=0V, V_{DS}=0V, f=1\text{MHz}$	-	1.9	-	Ω
Transconductance	g_{fs}	$V_{DS}=50V, I_D=1.5A$	-	4.8	-	S
Input Capacitance	C_{iss}	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1\text{ MHz}$	-	600	-	pF
Output Capacitance	C_{oss}		-	44	-	
Reverse Transfer Capacitance	C_{rss}		-	20	-	
Total Gate Charge	Q_g	$V_{DS} = 720\text{ V}, V_{GS} = 0/10\text{ V},$ $I_D = 3\text{ A}$	-	16	-	nC
Gate- Source charge	Q_{gs}		-	4	-	
Gate-Drain charge	Q_{gd}		-	7	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{DS} = 450\text{ V}$	-	26	-	ns
Turn-Off Delay Time	$t_{d(off)}$	$V_{GS} = 10\text{ V}$	-	42	-	
Rise time	t_r	$I_D = 3\text{ A}$ $R_G = 25\Omega$	-	48	-	
Fall time	t_f	$T_J = 25^\circ\text{C}$	-	33	-	

Diode Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Condition	Value			Unit
			min.	typ.	max.	
Diode Continuous Forward Current	I_S	$T_C=25^\circ\text{C}$	-	-	3	A
Pulsed Diode Forward Current	I_{SM}		-	-	12	
Diode Forward Voltage	V_{SD}	$I_S = 3A$ $T_J = 25^\circ\text{C}$	-	-	1.5	V
Reverse Recovery Time	t_{rr}	$V_R = 450\text{ V}, I_S = 3\text{ A},$	-	420	-	ns
Reverse Recovery Charge	Q_{rr}	$di/dt = 100\text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	-	3.3	-	μC

Typical Performance Characteristics

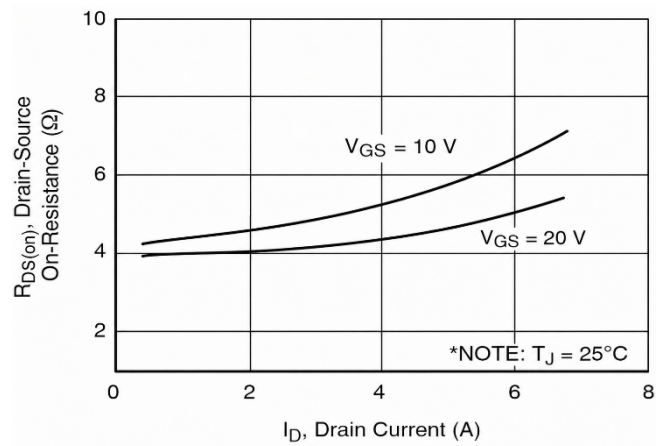
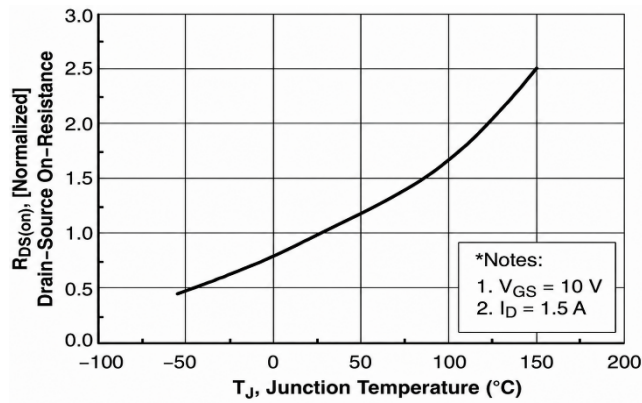
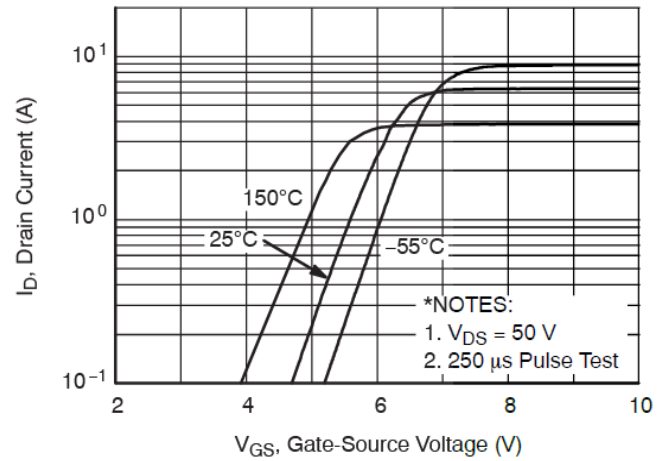
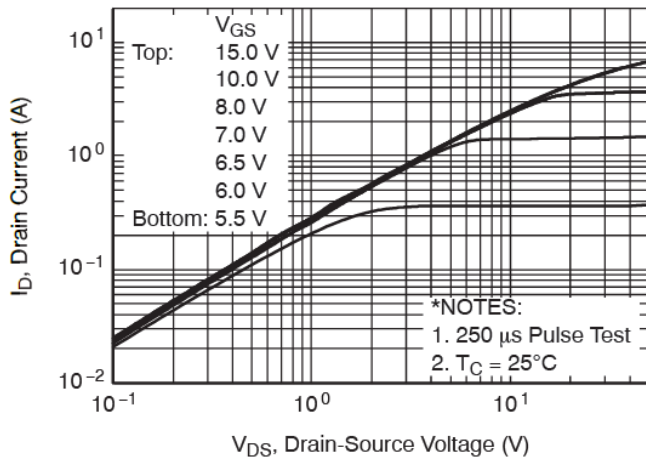
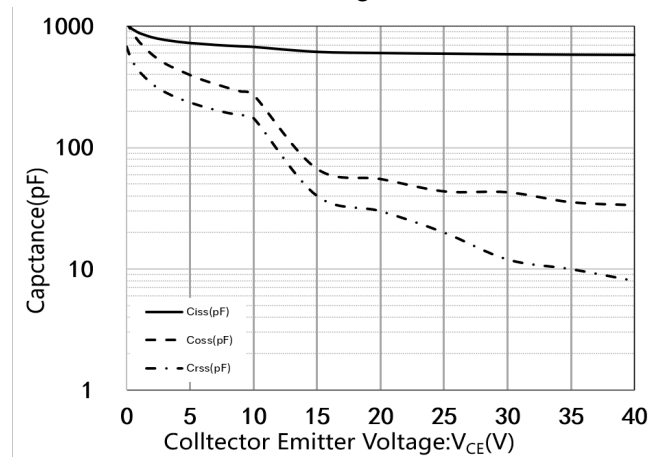
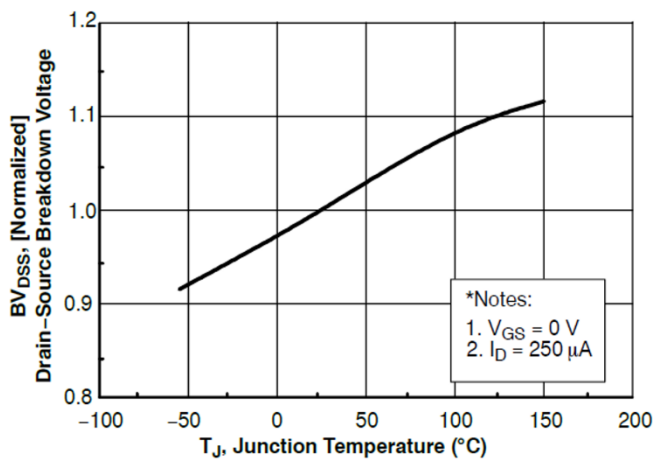
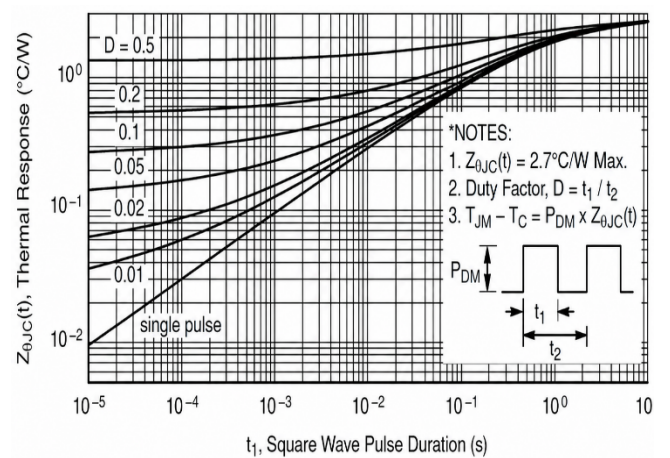
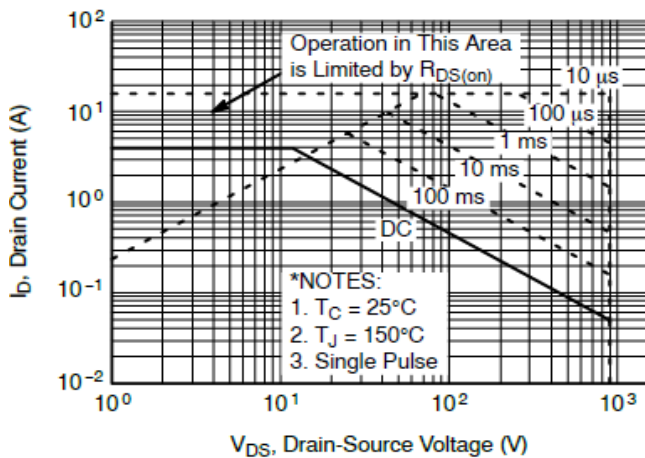
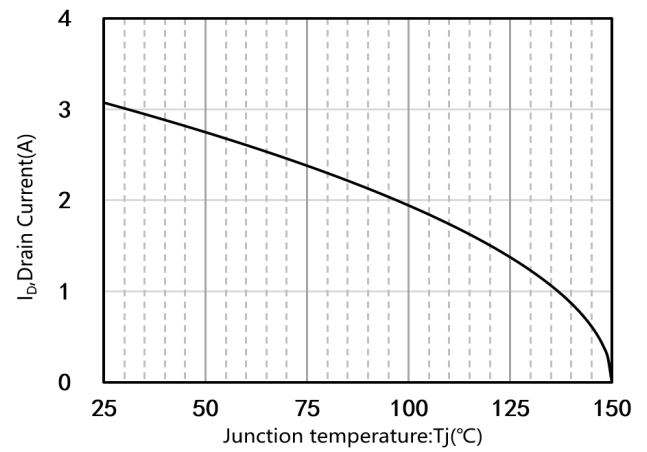
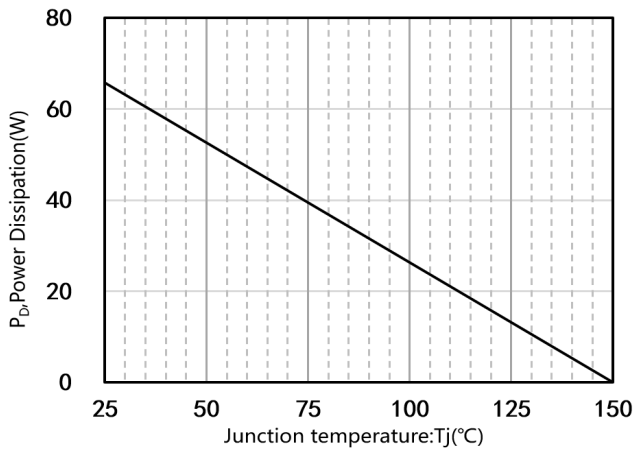
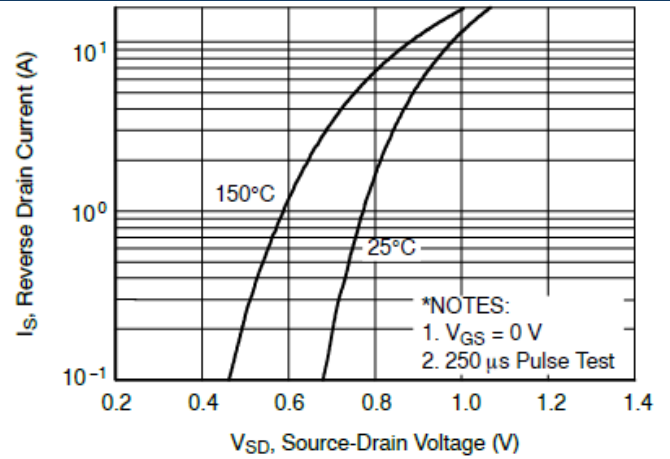
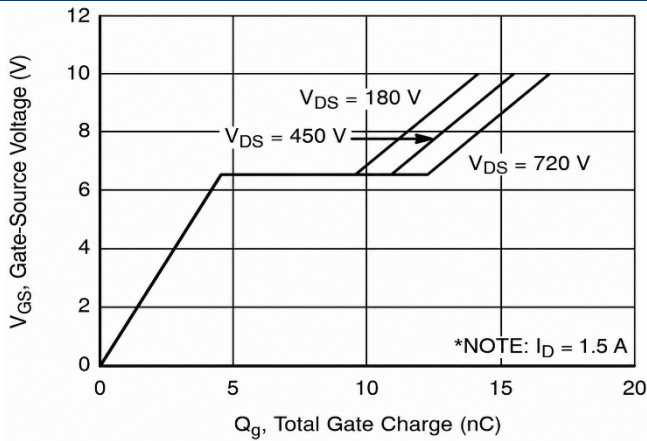
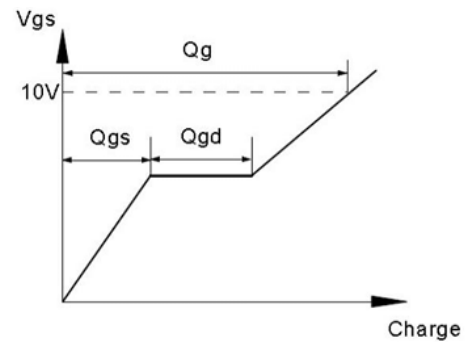
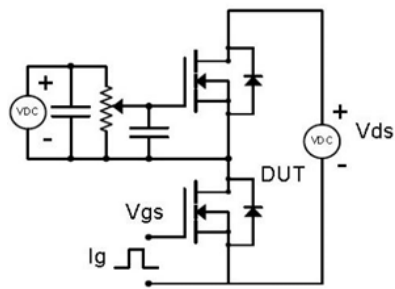


Fig 3. On-Resistance vs. Junction Temperature

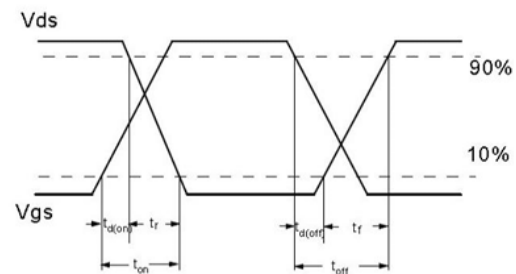
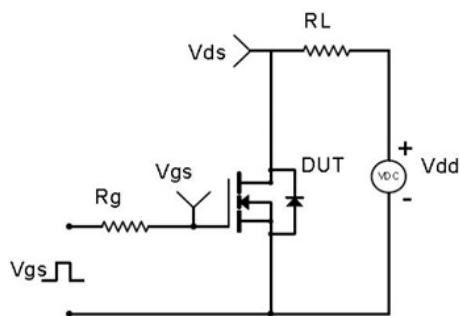




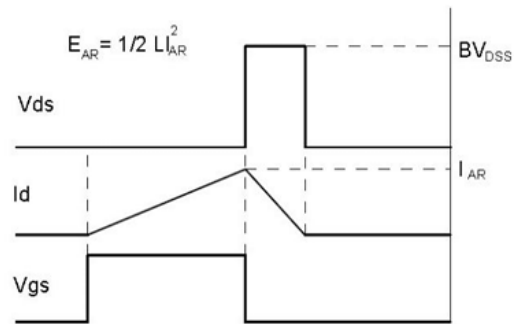
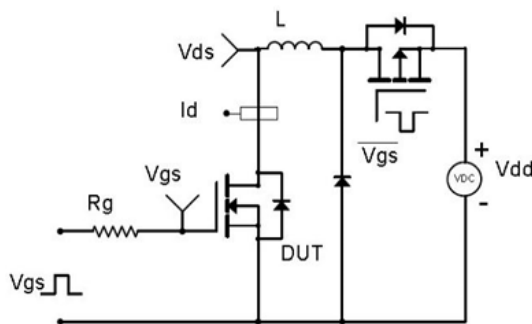
Test Circuit & Waveform



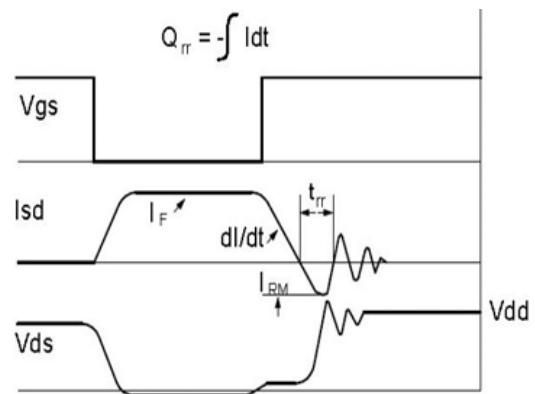
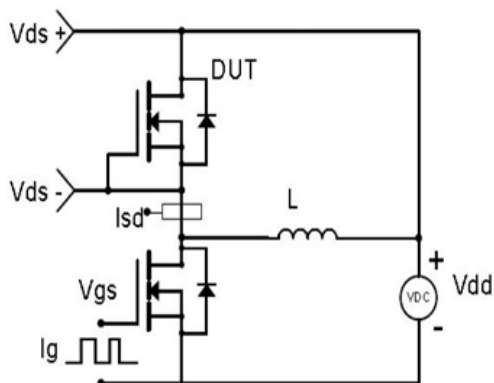
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



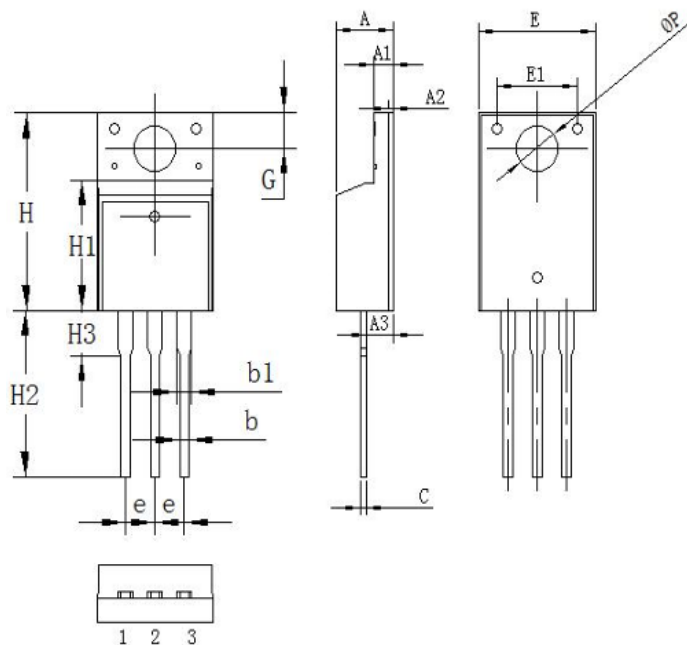
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

Package Information

基本尺寸



Symbol	单位 mm		
	Min	Nom	Max
A	4.55	4.75	4.95
A1	2.40	2.60	2.80
A2	0.40	0.60	0.80
A3	2.10	2.30	2.50
b1	1.10	1.30	1.50
b	0.60	0.80	1.00
c	0.42	0.50	0.58
e	2.30	2.50	2.70
E	9.9	10.1	10.3
E1	6.8	7	7.2
H	15.8	16.0	16.2
H1	9.10	9.30	9.50
H2	12.5	13.0	13.5
H3	3.10	3.30	3.50
G	3.00	3.20	3.40
ΦP	3.00	3.20	3.40

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-Headquarters

WuXi Thunder Microelectronics Incorporated Limited

Building E1-9, No.200 LingHu Road, XinWu district,WuXi,China 214135

Tel:+86-510-85160109 Fax:+86-510-85160109